

Notice of References Cited	Application/Control No. 09/896,975		Applicant(s)/Patent Under Reexamination CRUTCHFIELD ET AL.	
	Examiner Jacob Meek		Art Unit 2637	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-4,280,221	07-1981	Chun et al.	375/288
*	C	US-5,696,777	12-1997	Hofsaess, Michael	714/820
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IEEE 100 : the authoritative dictionary of IEEE standards terms. Author: IEEE; Imprint: New York : IEEE Press, 2000 pages 302 and 304
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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